



## DECLARATION OF EMC COMPLIANCE

**For**

OPTCORE TECHNOLOGY (HK) LIMITED

OPTICAL TRANSCEIVER

Model No. : OSP1250-XXXXXXR

Prepared for : OPTCORE TECHNOLOGY (HK) LIMITED  
Address : FLAT C, 23/F, LUCKY PLAZA, 315-321 LOCKHART  
ROAD, WANCHAI HONG KONG

Prepared by : Shenzhen Certification Technology Service Co., Ltd.  
Address : 3F, Bldg27, Area A, Tanglang Industrial Zone, Xili Town,  
Nanshan District, Shenzhen, Guangdong, P.R. China.

Report No. : STE110711603

Date of Test : July 12, 2011

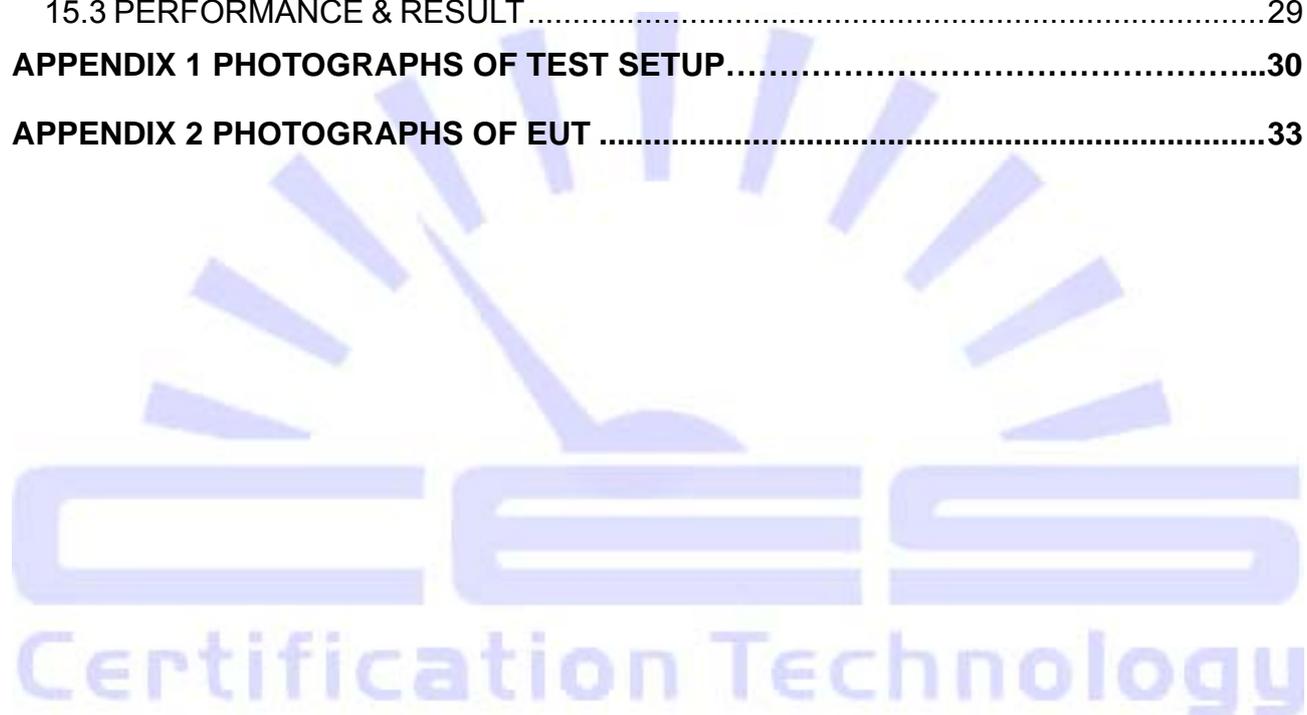
Date of Report : July 13, 2011

Version Number : REV0

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## EMC TEST VERIFICATION

Applicant: OPTCORE TECHNOLOGY (HK) LIMITED  
Address: FLAT C, 23/F, LUCKY PLAZA, 315-321 LOCKHART ROAD,  
WANCHAI HONG KONG  
Manufacturer: OPTCORE TECHNOLOGY (HK) LIMITED  
Address: FLAT C, 23/F, LUCKY PLAZA, 315-321 LOCKHART ROAD,  
WANCHAI HONG KONG  
Equipment Under Test: OPTICAL TRANSCEIVER  
Model Number: OSP1250-XXXXXXR  
Serial Number: N/A  
Trademark: OPTCORE

Measurement Procedure Used:

**EN 55022:2006+A1:2007**  
**EN 55024:1998+A1:2001+A2:2003**  
**EN 61000-3-2:2006+A1:2009+A2:2009**  
**EN 61000-3-3:2008**

The above equipment was tested by Shenzhen Certification Technology Service Co., Ltd. for compliance with the requirements in EMC Directive 2004/108/EC and the Technical Standards mentioned above. This configuration described in this report shows the maximum emission levels emanating from equipment and the level of the immunity endurance of the equipment are within the compliance requirements. We have recorded the worst sample condition of the EUT.

The test results of this report relate only to the tested sample identified in this report.

Date of Test : July 12, 2011

Prepared by :

*Amy Xiao*  
\_\_\_\_\_  
(Amy Xiao),



Approved & Authorized Signer:

*simple*  
\_\_\_\_\_  
(Simple Guan)

## 1 SYSTEM DESCRIPTION

### Describe the Sequence:

1. Connected the EUT to support device. then running applicable function.
2. Make sure the EUT work normally during the whole test.

## 2 PRODUCT INFORMATION

Technical Data: DC 3.3V

## 3 EXTERNAL PERIPHERAL DEVICES

Device Type	Manufacturer	Model Name	Serial No.	Data cable	Power cable
N/A	N/A	N/A	N/A	N/A	N/A



## 4 TEST FACILITY

### 4.1 Laboratory Name:

Shenzhen Certification Technology Service Co., Ltd.

### 4.2 Site Location :

3F, Bldg.27, Area A, Tanglang Industrial Zone, Xili Town,  
Nanshan District, Shenzhen 518055, Guangdong, P.R. China

### 4.3 Test facility:

JAN 7, 2008 File on Federal Communication Commission  
Registration Number:305283

October 5, 2009 Certificated by IC  
Registration Number: 8285A

August 4, 2010 Certificated by CNAS  
Registration Number: L4656

DEC. 29, 2008 Certificated by CEC  
Registration No.:CA 95814-5512

DEC. 31, 2008 Accredited by TUV Rheinland Guangzhou  
Audit Report: 17006916001

NOV. 17, 2008 Accredited by SGS  
Registration Number: SWL-017

NOV. 18, 2008 Accredited by NEMKO  
Registration Number: 17025

## 5 TEST EQUIPMENT LIST

**Instrumentation:** The following list contains equipment used at Most for testing. The equipment conforms to the CISPR 16-1 / ANSI C63.4 Specifications for Electromagnetic Interference and Field Strength Instrumentation from 10 kHz to 1.0GHz or above.

### Equipment used during the tests:

Test Equipment List				
Equipment Type	Manufacturer	Model Number	Serial Number	Calibration Date
Spectrum Analyzer	Agilent	E4443A	MY46185649	09/07/2010
Biconilog Antenna	ETS	3142C	920250	05/18/2011
Multi device Controller	ETS	2090	00057230	06/06/2011
Receiver	R&S	ESCI	100435	05/18/2011
LISN	ETS	3816	00060336	09/07/2010
Receiver	R&S	ESCI	100435	05/18/2011
Absorbing clamp	Schwarzbeck wess-eietronik	MDS21	3717	11/27/2010
Harmonic Emission Flicker	California instruments	500LIX-40 0-CTS	N/A	05/18/2011
ESD Simulator	EM-Test	ESD 30C/P30C	V0603101091	08/23/2010
Signal Generator	IFA	2023B	202307/883	05/18/2011
Power Amplifier	AR	150W100 0	0322288	05/18/2011
Power Amplifier	AR	25S1G4A	321112	05/18/2011
Compact Generator	EM-Test	UCS500M /6B	V0603101093	09/07/2010
Capacitive Clamp	EM-Test	C Clamp HFK	0306-43	09/04/2010
CDN for Telecom Port	EM-Test	CNV504S 1	V0603101094	09/07/2010
Surge Signal Generator	SCHAFFNER	NSG2050	200313-135A R	07/11/2010
EFT Signal Generator	SCHAFFNER	NSG2025	19878	09/07/2010

<b>Test Equipment List</b>				
<b>Equipment Type</b>	<b>Manufacturer</b>	<b>Model Number</b>	<b>Serial Number</b>	<b>Calibration Date</b>
Power Amplifier	AR	75A250A	329207	09/07/2010
CDN	EM-Test	CDN M2/M3	0204-01	09/07/2010
Direction Coupler	EM-Test	DC2600A	312711	06/06/2011
EM-Clamp	EM-Test	EM101	35770	09/07/2010
Calibration	EM-Test	CAM2/M3	0206-65	06/06/2011
Attenuator	EM-Test	ATT6/75	0320837	06/06/2011
Power Sensor	AR	PH2000	321149	11/08/2010
Power Meter	AR	PM2002	312901	11/08/2010
Signal Generator	IFA	2023B	202307/439	09/07/2010



## 6 EN 55022 CONDUCTED EMISSION TEST

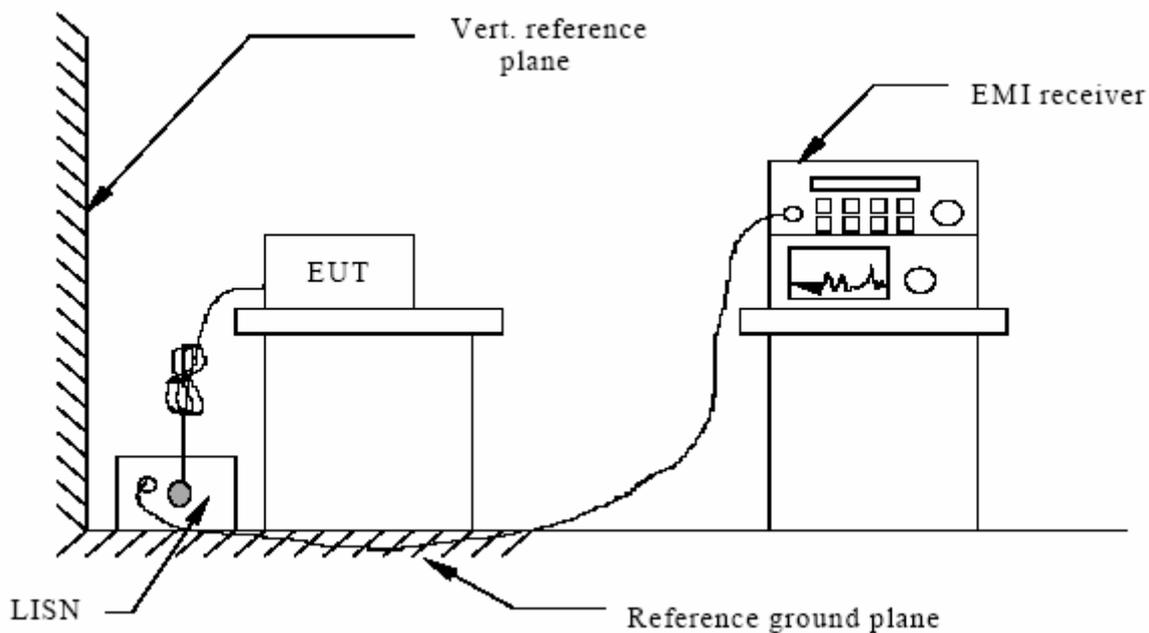
### 6.1 LIMITS OF CONDUCTED EMISSION TEST

Frequency	Maximum RF Line Voltage	
	Q.P.( dBuV)	Average( dBuV)
150kHz-500kHz	66-56	56-46
500kHz-5MHz	56	46
5MHz-30MHz	60	50

**\*\*Note:** 1. The lower limit shall apply at the transition frequency.

2. The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.50 MHz

### 6.2 BLOCK DIAGRAM OF TEST SETUP



### **6.3 PROCEDURE OF CONDUCTED EMISSION TEST**

The EUT and support equipment was set up on the test bench.  
A scan was taken on each power line, Line 1 and Line 2, record at least six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If the EUT emission level was less  $-2\text{dB}$  to the A.V. limit in Peak mode, then the emission signal was re-checked using Q.P and Average detector.  
The test data of the worst case condition(s) was reported on the Summary Data page.

### **6.4 TEST RESULT OF CONDUCTED EMISSION TEST**

EUT Supply by DC Power, So it not applicable.



## 7 EN 55022 RADIATED EMISSION TEST

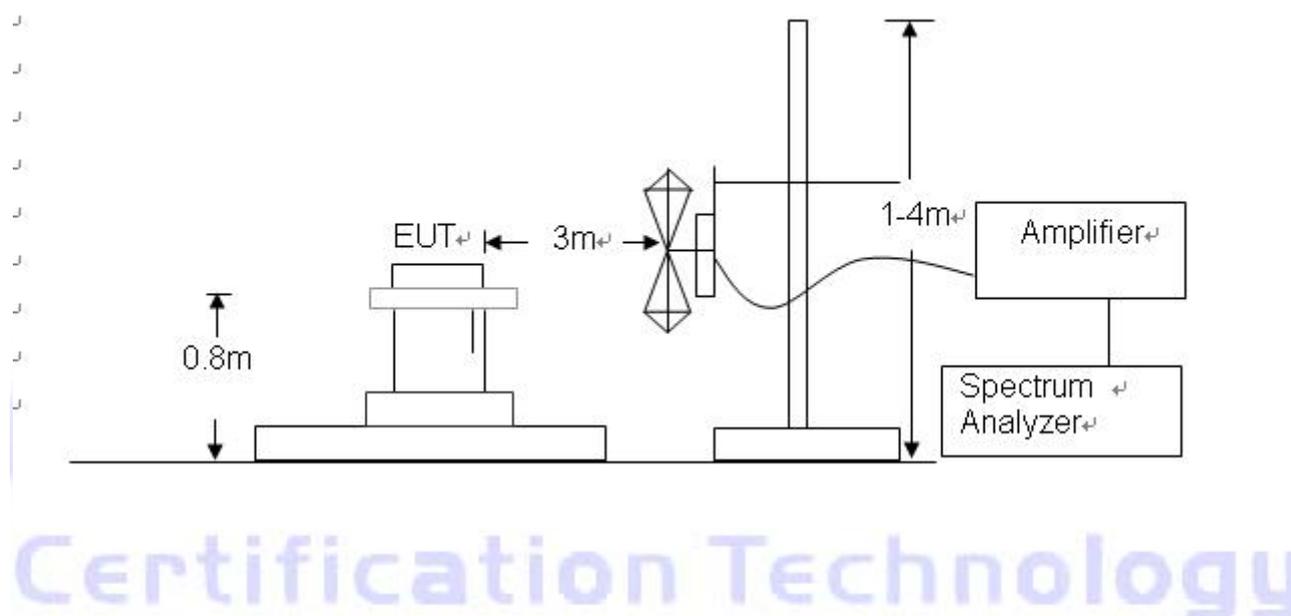
### 7.1 LIMITS OF RADIATED DISTURBANCES AT 3M DISTANCES

Frequency (MHz)	Distance (m)	Maximum Field Strength Limit (dBuV/m Q.P.)
30-230	3	40.00
230-1000	3	47.00

**\*\*Note:** The lower limit shall apply at the transition frequency.

### 7.2 BLOCK DIAGRAM OF TEST SETUP

System Diagram of Connections between EUT and Simulators



### 7.3 PROCEDURE OF RADIATED EMISSION TEST

The EUT and support equipment were set up on the turntable.

The Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

Record at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and Q.P./Peak reading is presented.

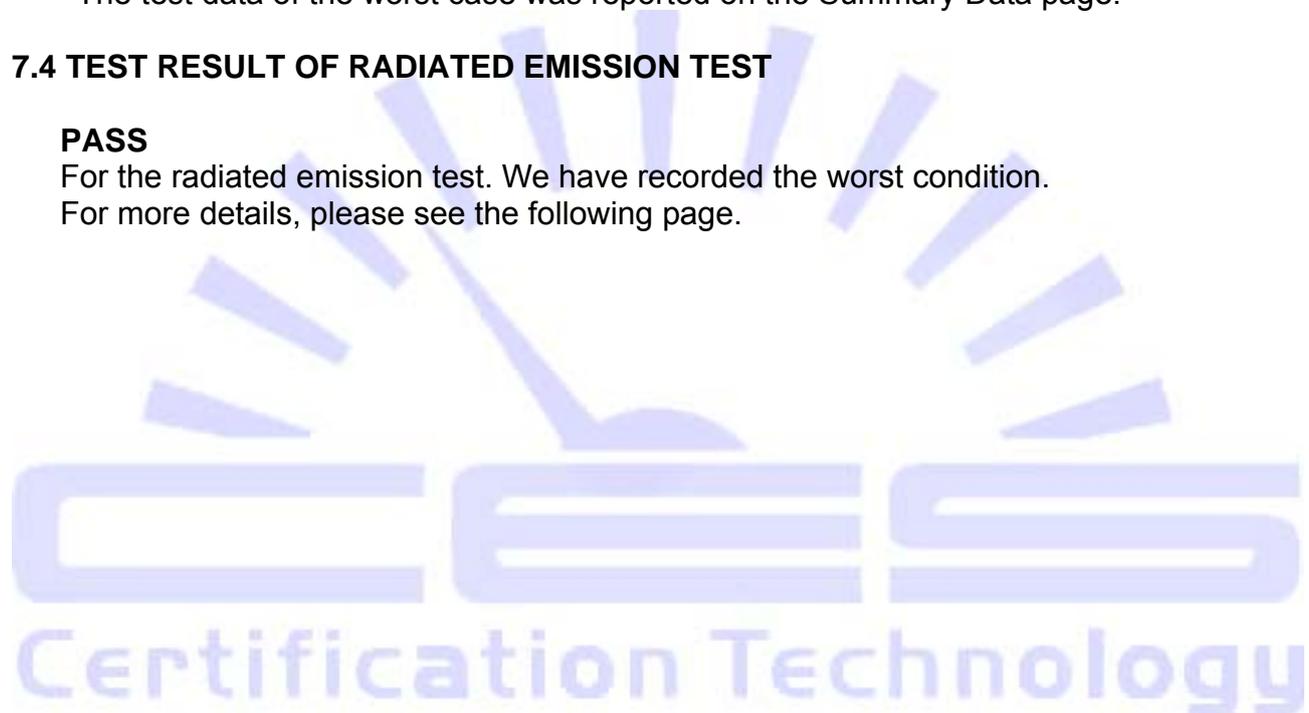
The test data of the worst case was reported on the Summary Data page.

### 7.4 TEST RESULT OF RADIATED EMISSION TEST

#### **PASS**

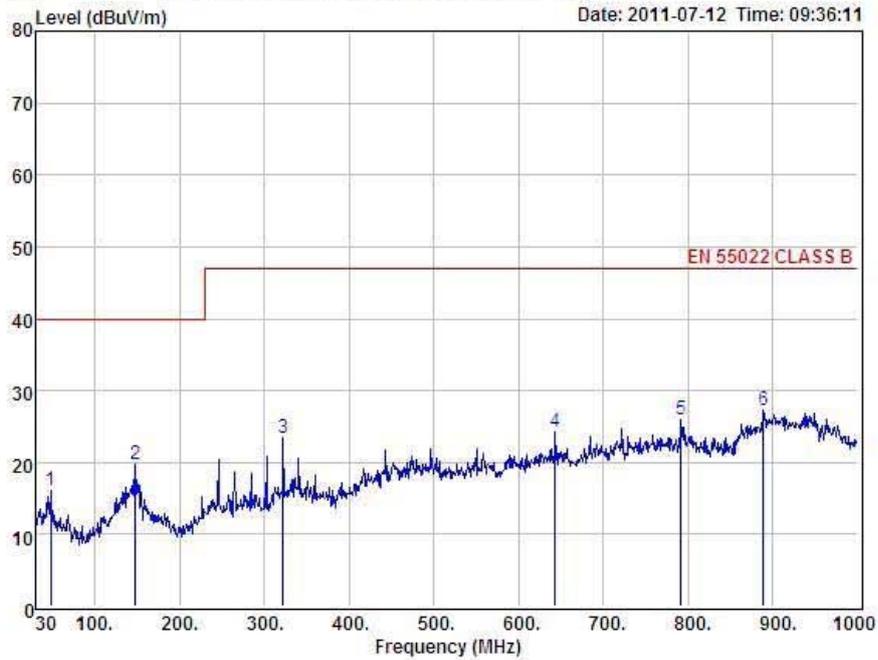
For the radiated emission test. We have recorded the worst condition.

For more details, please see the following page.





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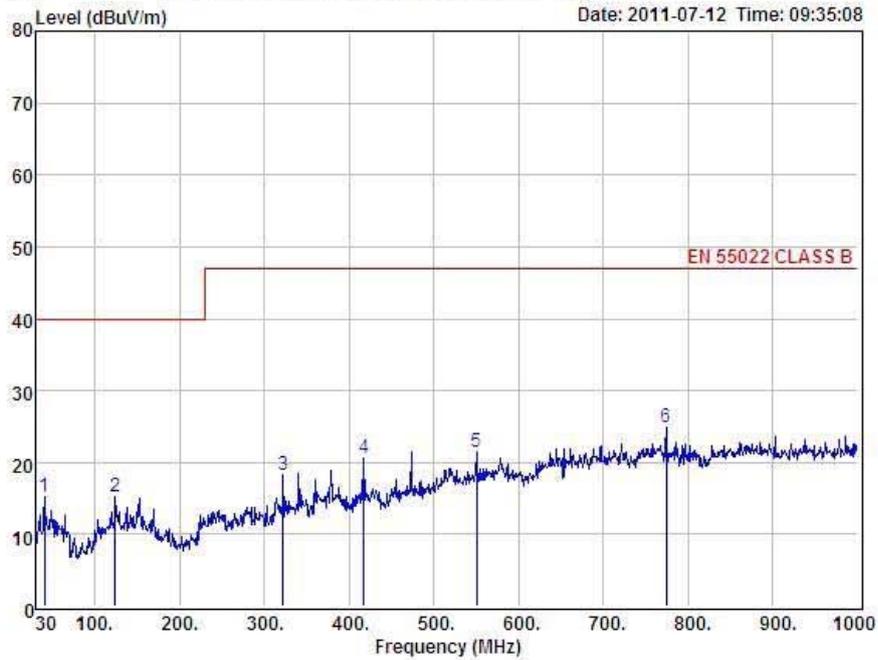


Condition : EN 55022 CLASS B 3m POL: HORIZONTAL  
 EUT : OPTICAL TRANSCEIVER  
 Model No. : DSP1250-XXXXXXR  
 Test Mode : Normal  
 Power :  
 Test Engineer : Store  
 Remark :

Item	Freq MHz	Read Level dBuV	Antenna Factor dB	Preamp Lose dB	Cable dB	Level dBuV	Limit dBuV	Margin dBuV	Remark
1	47.46	31.78	13.59	29.82	0.59	16.14	40.00	-23.86	QP
2	147.37	33.63	13.90	28.90	1.12	19.75	40.00	-20.25	QP
3	321.97	37.20	13.38	29.23	2.05	23.40	47.00	-23.60	QP
4	643.04	31.72	19.02	29.79	3.29	24.24	47.00	-22.76	QP
5	791.45	31.29	20.65	29.65	3.58	25.87	47.00	-21.13	QP
6	888.45	31.57	21.51	29.65	3.78	27.21	47.00	-19.79	QP



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Condition : EN 55022 CLASS B 3m POL: VERTICAL  
 EUT : OPTICAL TRANSCEIVER  
 Model No. : DSP1250-XXXXXXR  
 Test Mode : Normal  
 Power :  
 Test Engineer : Store  
 Remark :

Item	Freq MHz	Read Level dBuV	Antenna Factor dB	Preamp Lose dB	Cable dB	Level dBuV	Limit dBuV	Margin dBuV	Remark
1	40.67	30.33	14.07	29.81	0.55	15.14	40.00	-24.86	QP
2	124.09	30.72	12.46	28.88	0.99	15.29	40.00	-24.71	QP
3	321.97	31.95	13.38	29.23	2.05	18.15	47.00	-28.85	QP
4	417.03	32.35	15.18	29.45	2.56	20.64	47.00	-26.36	QP
5	549.92	30.77	17.39	29.71	3.10	21.55	47.00	-25.45	QP
6	773.99	30.55	20.54	29.67	3.55	24.97	47.00	-22.03	QP

## 8 EN 61000-3-2 POWER HARMONICS TEST

### POWER HARMONICS MEASUREMENT

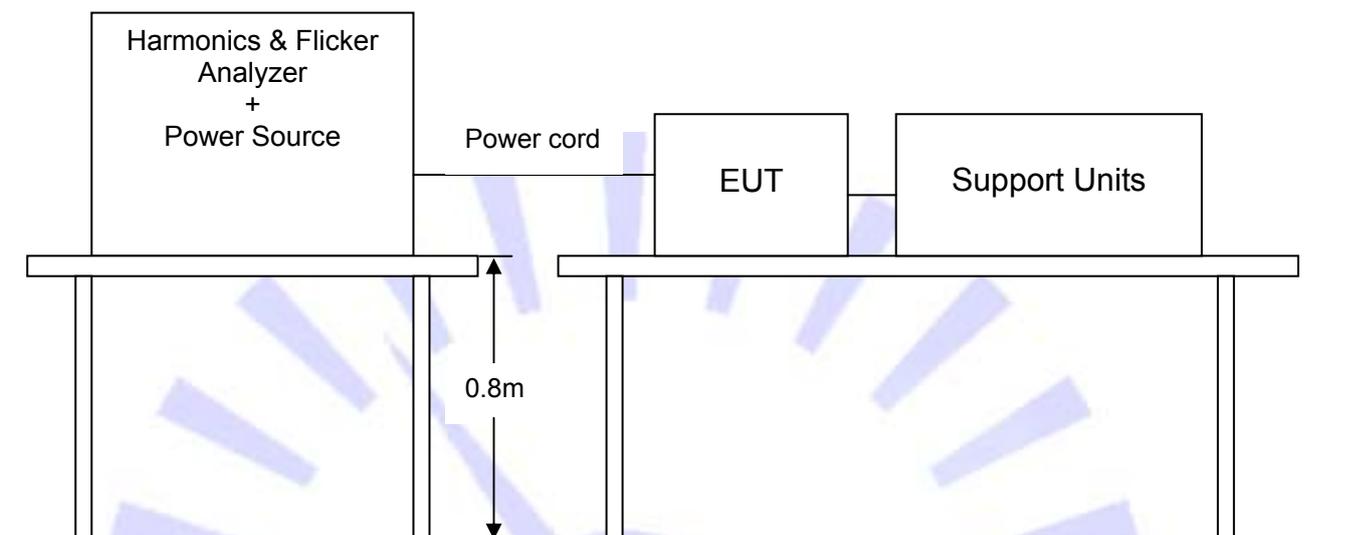
**Basic Standard** : EN 61000-3-2:2006+A1:2009+A2:2009

**Limits** : CLASS A, CLASS B, CLASS C, CLASS D

**Temperature** : 25°C

**Humidity** : 55%

### 8.1 BLOCK DIAGRAM OF TEST SETUP



### 8.2 RESULT

EUT Supply by DC Power, So it not applicable.

## 9 EN 61000-3-3 VOLTAGE FLUCTUATION / FLICKER TEST

### VOLTAGE FLUCTUATION/FLICKER MEASUREMENT

**Basic Standard** : EN 61000-3-3:2008

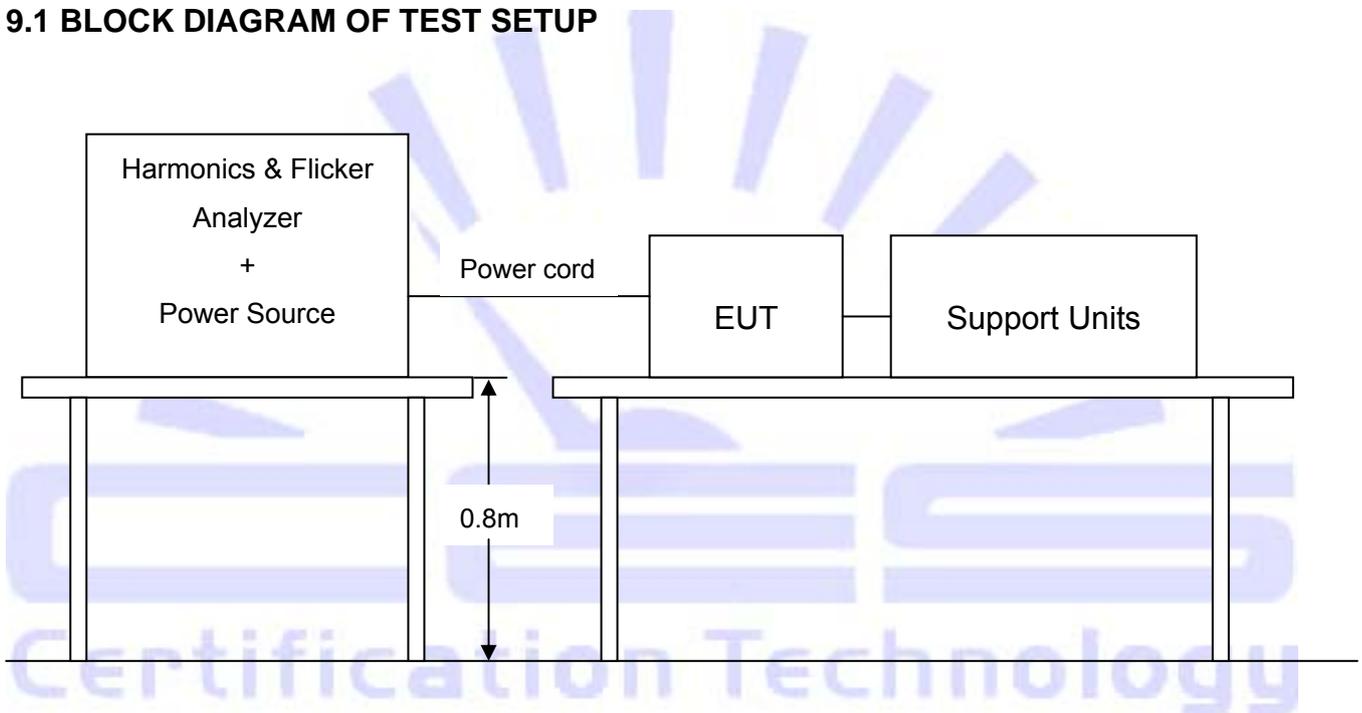
**Limits** : §5 of EN 61000-3-3

**Temperature** : 25°C

**Humidity** : 55%

**EUT** : OPTICAL TRANSCEIVER

### 9.1 BLOCK DIAGRAM OF TEST SETUP



### 9.2 RESULT

EUT Supply by DC Power, So it not applicable.

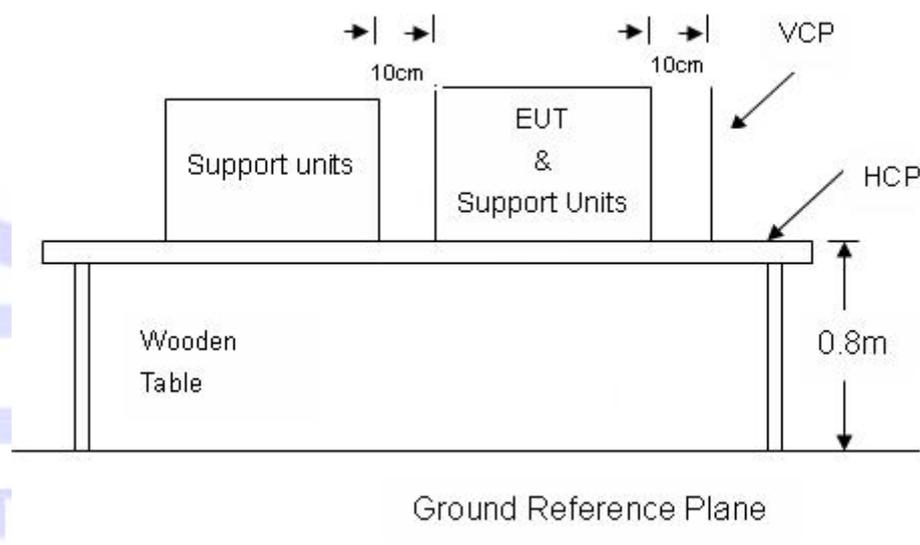
## 10 IEC 61000-4-2 ESD TEST

### ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

<b>Basic Standard</b>	:	IEC 61000-4-2: 2008
<b>Test Level</b>	:	± 8 kV (Air Discharge) ± 4 kV (Contact Discharge) ± 4 kV (Indirect Discharge)
<b>Standard require</b>	:	B
<b>Temperature/Humidity</b>	:	25°C/55%
<b>EUT</b>	:	OPTICAL TRANSCEIVER

#### 10.1 BLOCK DIAGRAM OF TEST SETUP

*(The 470 k ohm resistors are installed per standard requirement)*



#### 10.2 TEST PROCEDURE

The EUT was located 0.1 m minimum from all sides of the HCP.

Make sure the EUT work normally.

As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of the EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of the EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 20 indirect discharges (contact) to the front edge of horizontal coupling plane.

Other parts of the EUT where it is not possible to perform contact discharge then selecting appropriate points of the EUT for air discharge, a minimum of 10 single air discharges shall be applied.

The application of ESD to the contact of open connectors is not required.

The following test condition was followed during the tests.

The electrostatic discharges were applied as follows:

Amount of Discharges	Voltage	Coupling	Result
Mini 10 /Point	±4kV	Contact Discharge	Pass
Mini 10 /Point	±4kV	Indirect Discharge HCP	Pass
Mini 10 /Point	±4kV	Indirect Discharge VCP	Pass
Mini 10 /Point	±8kV	Air Discharge	Pass

### 10.3 PERFORMANCE & RESULT

- Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

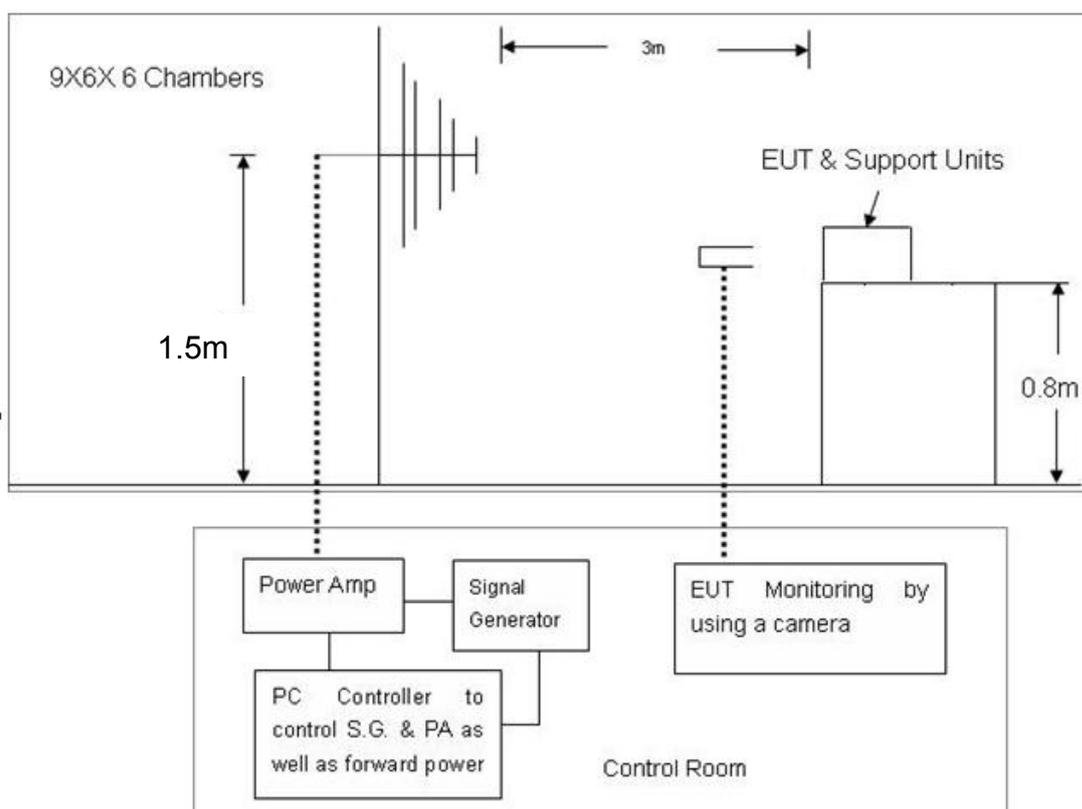
**PASS**       **FAIL**

## 11 IEC 61000-4-3 RS TEST

### RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

**Basic Standard** : IEC 61000-4-3:2008  
**Requirements** : 3 V/m with 80% AM. 1kHz Modulation.  
**Standard require** : A  
**Temperature** : 25°C  
**Humidity** : 55%  
**EUT** : OPTICAL TRANSCEIVER

#### 11.1 BLOCK DIAGRAM OF TEST SETUP



## 11.2 TEST PROCEDURE

The EUT was located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity. The support units were located outside of the uniformity area, but the cable(s) connected with the EUT were exposed to the calibrated field as per IEC 61000-4-3.

Make sure the EUT work normally.

Set the testing parameters of RS test software as per IEC 61000-4-3.

From the result of pre-test in step 5, choose the worst side of EUT for final test from 80 MHz to 1000 MHz at 1% steps.

Record the test result in following table.

### IEC 61000-4-3 test conditions:

Sweep Step : 1%  
 Modulation : 1 KHz 80% AM  
 Dwell Time : 1 s

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result
80-1000	3V/m	Yes	H	Front	Pass
80-1000	3V/m	Yes	H	Left	Pass
80-1000	3V/m	Yes	H	Back	Pass
80-1000	3V/m	Yes	H	Right	Pass
80-1000	3V/m	Yes	V	Front	Pass
80-1000	3V/m	Yes	V	Left	Pass
80-1000	3V/m	Yes	V	Back	Pass
80-1000	3V/m	Yes	V	Right	Pass

### 11.3 PERFORMANCE & RESULT

- Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
- Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

**PASS**       **FAIL**



## 12 IEC 61000-4-4 EFT TEST

### ELECTRICAL FAST TRANSIENTS/BURST IMMUNITY TEST

**Basic Standard** : IEC 61000-4-4:2004+A1:2006+A2:2007

**Requirements** : +/- 1kV for Power Supply Lines

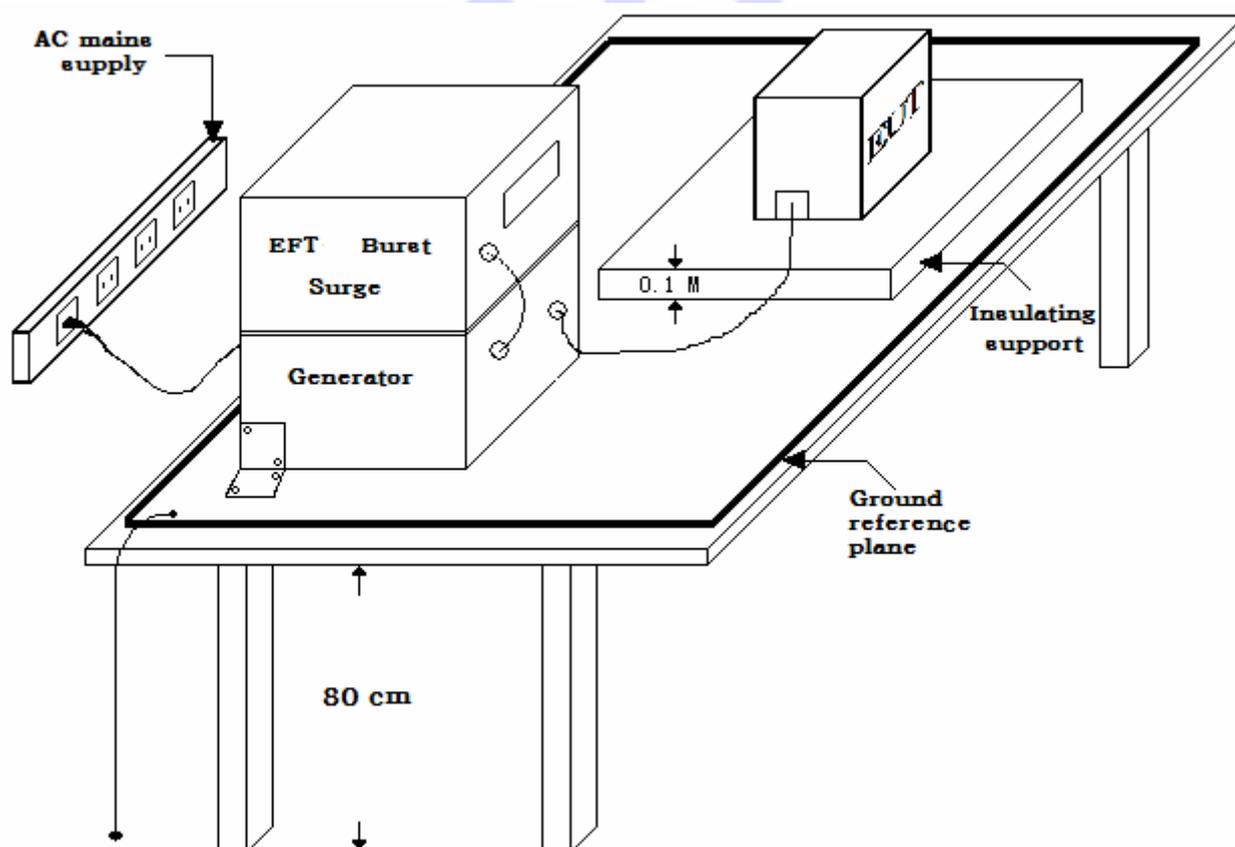
**Standard require** : B

**Temperature** : 25°C

**Humidity** : 55%

**EUT** : OPTICAL TRANSCEIVER

### 12.1 BLOCK DIAGRAM OF TEST SETUP



## 12.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8m away from ground reference plane.

A 1.0 meter long power cord was attached to the EUT during the test.

The length of communication cable between communication port and clamp was keeping within 1 meter.

Make sure the EUT work normally.

Related peripherals work during the test.

Record the test result as shown in following table.

### Test conditions:

Frequency: 5kHz

Spike: 75

Wave Spec: 5/50ns

Duration: 2Min

Repeat Rate:300ms

Inject Line	Voltage( $\pm$ kV)	Inject Method	Result
L	1	Direct	Pass
N	1	Direct	Pass
L-N	1	Direct	Pass

## 12.3 PERFORMANCE & RESULT

**Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

**Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

**Criteria C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

EUT Supply by DC Power, So it not applicable.

### 13 IEC 61000-4-5 SUREG TEST

#### SURGE IMMUNITY TEST

**Basic Standard** : IEC 61000-4-5:2005+A1:2009

**Requirements** : +/- 1kV (Line to Line)  
: +/- 2kV (Line to Ground)

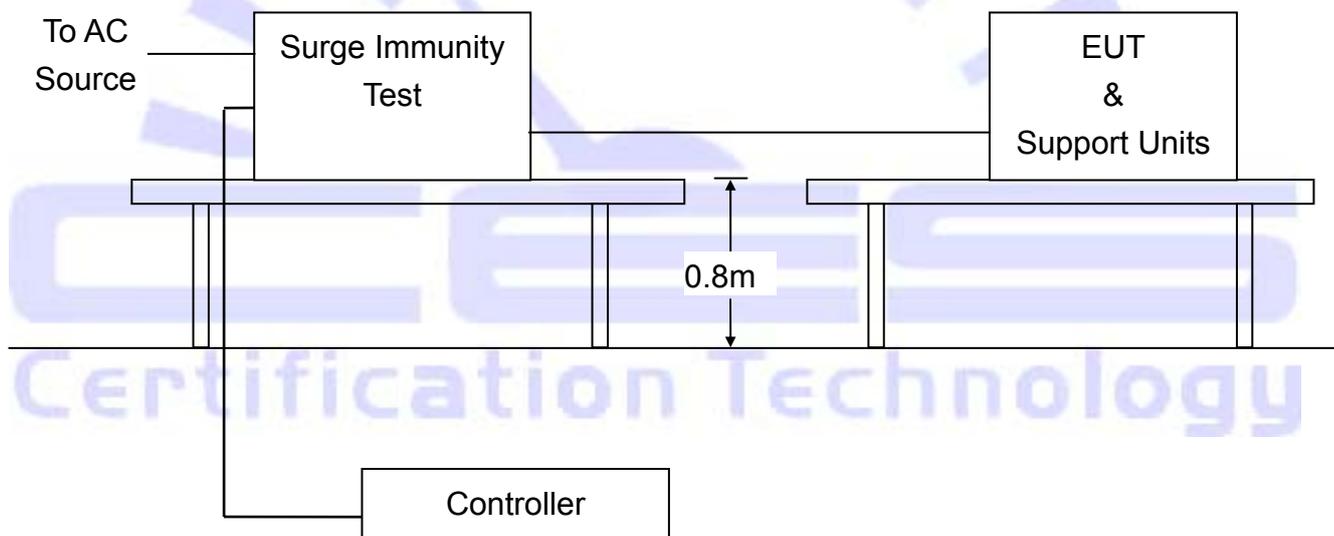
**Standard require** : B

**Temperature** : 25°C

**Humidity** : 55%

**EUT** : OPTICAL TRANSCEIVER

#### 13.1 BLOCK DIAGRAM OF TEST SETUP



### 13.2 TEST PROCEDURE

The EUT and support units were located on a wooden table 0.8 m away from the ground floor.

Make sure the EUT work normally.

Record the test result as shown in the following table.

**Test conditions:**

Repeat Rate : 60Sec.  
 Evaluation Times/Point : 5  
 Phase angle : 0°, 90°, 180°, 270°  
 Wave Spec. : 1.2/50uS

Coupling Line	Voltage (kV)	Polarity	Result
L-N	1	Positive	Pass
L-N	1	Negative	Pass

### 13.3 PERFORMANCE & RESULT

- Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
- Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
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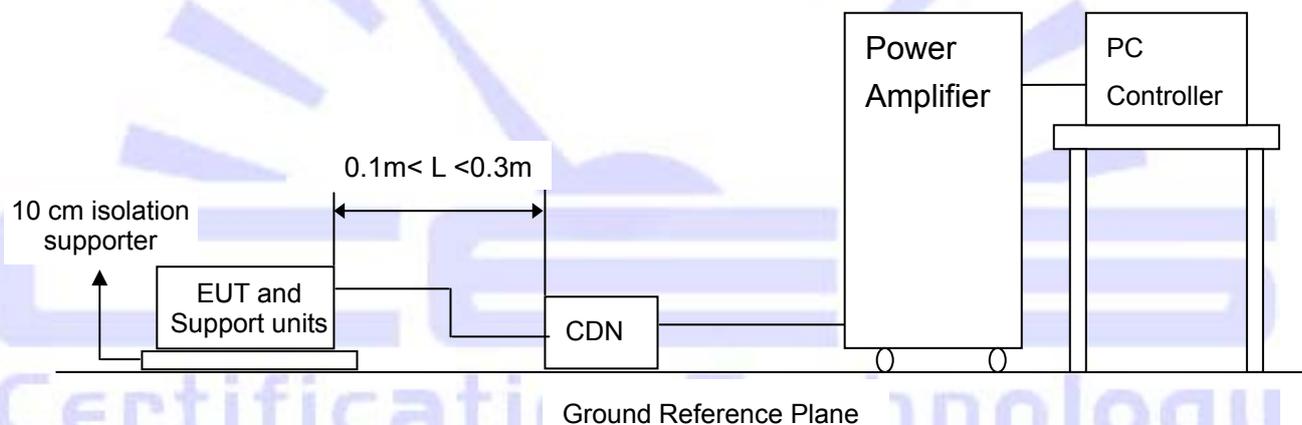
EUT Supply by DC Power, So it not applicable.

## 14 IEC 61000-4-6 CS TEST

### IEC 61000-4-6 IMMUNITY TO CONDUCTED DISTURBANCES, INDUCED BY RADIO-FREQUENCY FIELD

<b>Basic Standard</b>	: IEC 61000-4-6: 2008
<b>Requirements</b>	: 3V with 80% AM. 1 kHz Modulation
<b>Injection Method</b>	: CDN M2
<b>Standard require</b>	: A
<b>Temperature</b>	: 25°C
<b>Humidity</b>	: 55%
<b>EUT</b>	: OPTICAL TRANSCEIVER

#### 14.1 BLOCK DIAGRAM OF TEST SETUP



## 14.2 TEST PROCEDURE

The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.

Make sure the EUT work normally.

Related peripherals work during the test.

Set the testing parameters of CS test software per IEC 61000-4-6.

Record the test result in following table.

### Test conditions:

Sweep Step : 1%

Modulation : 1 KHz 80% AM

Range (MHz)	Strength	Modulation	Result
0.15-80	3V	Yes	Pass

## 14.3 PERFORMANCE & RESULT

**Criteria A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

**Criteria B:** The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.

**Criteria C:** Temporary loss of function is allowed, provided the functions self-recoverable or can be restored by the operation of controls.

EUT Supply by DC Power, So it not applicable.
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## 15 IEC 61000-4-11 DIPS TEST

### VOLTAGE DIPS, SHORT INTERRUPTIONS AND VOLTAGE VARIATIONS IMMUNITY TEST

**Basic Standard** : IEC 61000-4-11: 2005

**Requirement** : 100% 0.5 period; 30% 25 periods; 100% 250 periods.

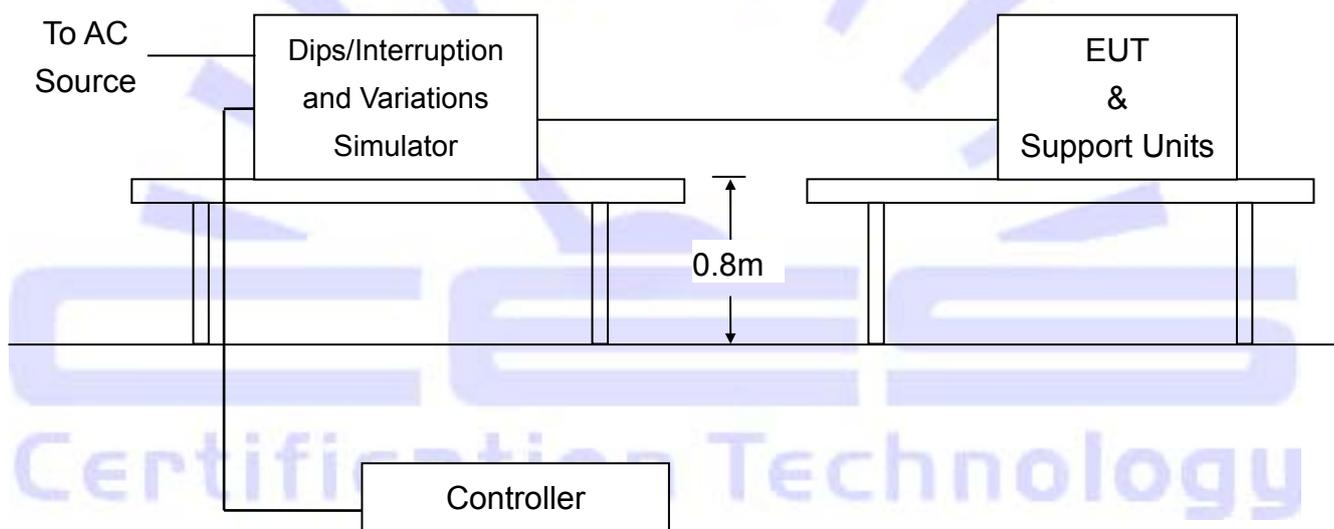
**Test Interval** : Min. 10 sec.

**Temperature** : 25°C

**Humidity** : 55%

**EUT** : OPTICAL TRANSCEIVER

#### 15.1 BLOCK DIAGRAM OF TEST SETUP



## 15.2 TEST PROCEDURE

The EUT and support units were located on a wooden table, 0.8 m away from the ground floor.

Make sure the EUT work normally.

Set the parameter of tests and then perform the test software of test simulator.

Conditions change to occur at 0 degree crossover point of the voltage waveform.

Record the test result in the test record form.

### Test conditions:

The duration with a sequence of three dips/interruptions with interval of 10 s minimum (Between each test event)

### Voltage Dips:

Test Level % $U_T$	Reduction (%)	Duration (ms)	Observation	Performance Criteria	Meet Performance Criteria
70	30	500	Normal	C	C

### Voltage Interruptions:

Test Level % $U_T$	Reduction (%)	Duration (ms)	Observation	Performance Criteria	Meet Performance Criteria
0	100	5000	Normal	C	C
0	100	10	Normal	B	B

## 15.3 PERFORMANCE & RESULT

EUT Supply by DC Power, So it not applicable.

**APPENDIX 1 PHOTOGRAPHS OF TEST SETUP**



### Radiated Emission Test Setup



### Electrostatic Discharge Test Setup





**APPENDIX 2 PHOTOGRAPHS OF EUT**

**Figure 1**

Photo of EUT

Front View

Rear View

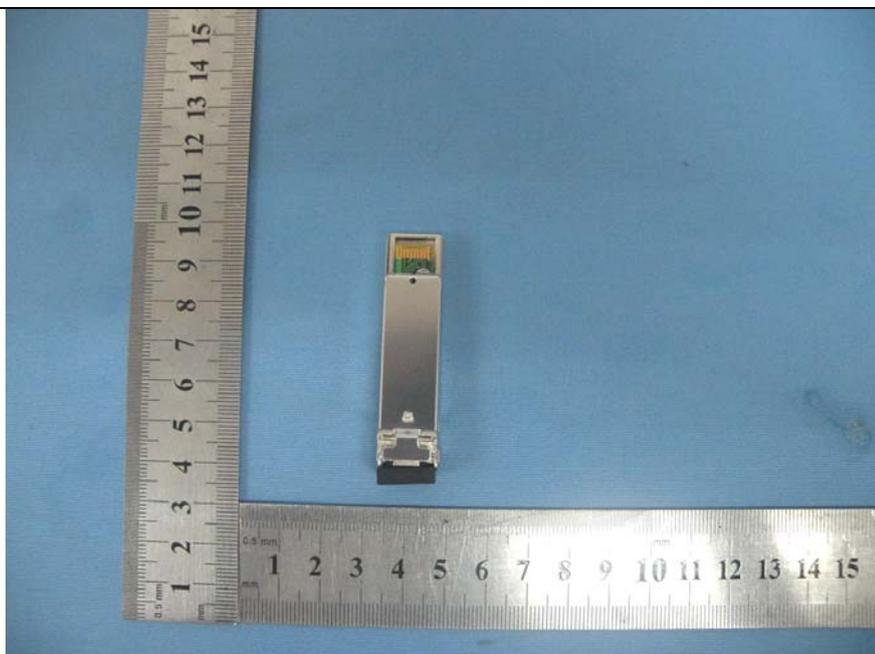
Top View

Bottom View

Left View

Right View

Inside View



**Figure 2**

Photo of EUT

Front View

Rear View

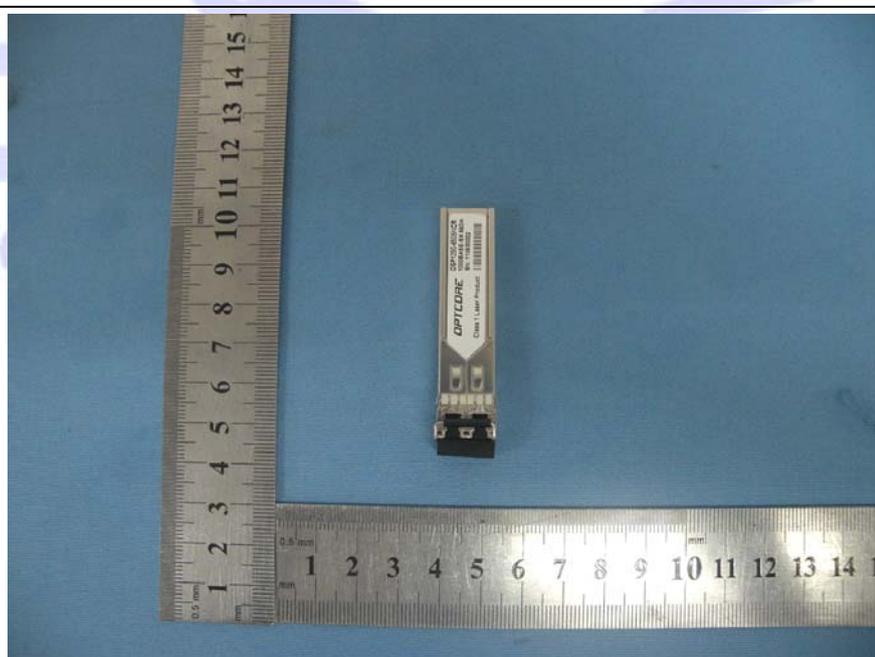
Top View

Bottom View

Left View

Right View

Inside View



**Figure 3**

Photo of EUT

Front View [ ]

Rear View [ ]

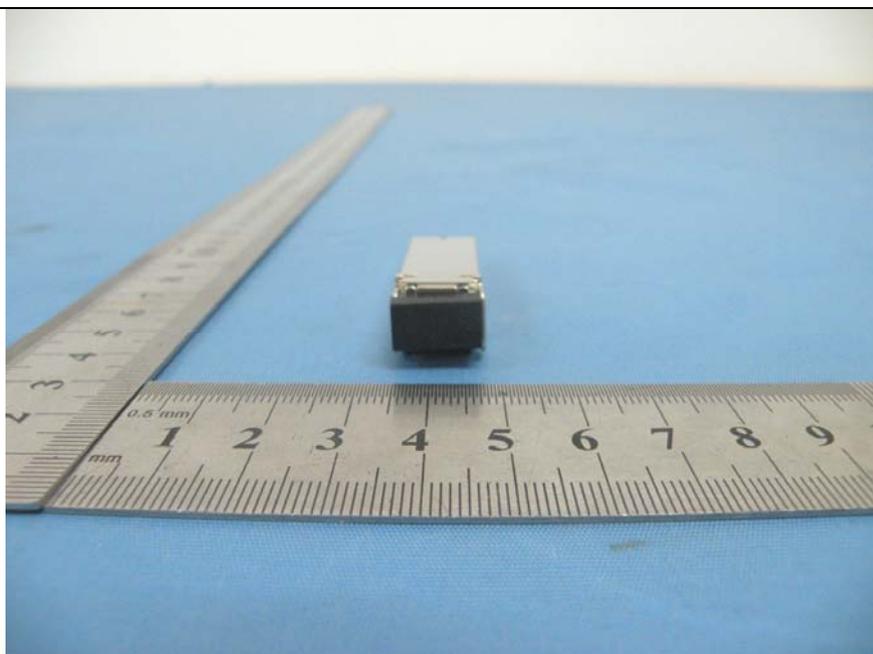
Top View [✓]

Bottom View [ ]

Left View [ ]

Right View [ ]

Inside View [ ]



**Figure 4**

Photo of EUT

Front View [ ]

Rear View [ ]

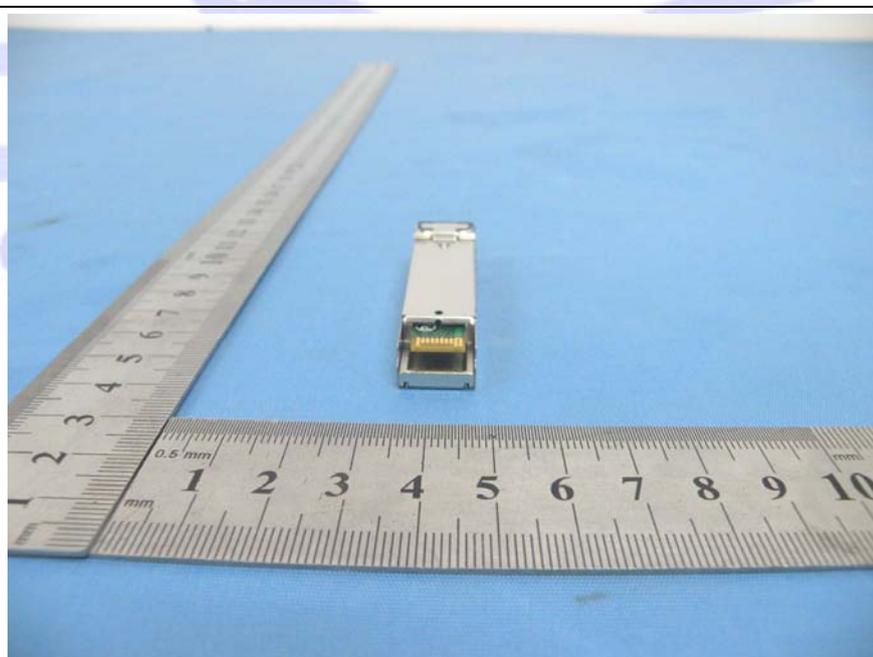
Top View [ ]

Bottom View [✓]

Left View [ ]

Right View [ ]

Inside View [ ]



**Figure 5**

Photo of EUT

Front View [ ]

Rear View [ ]

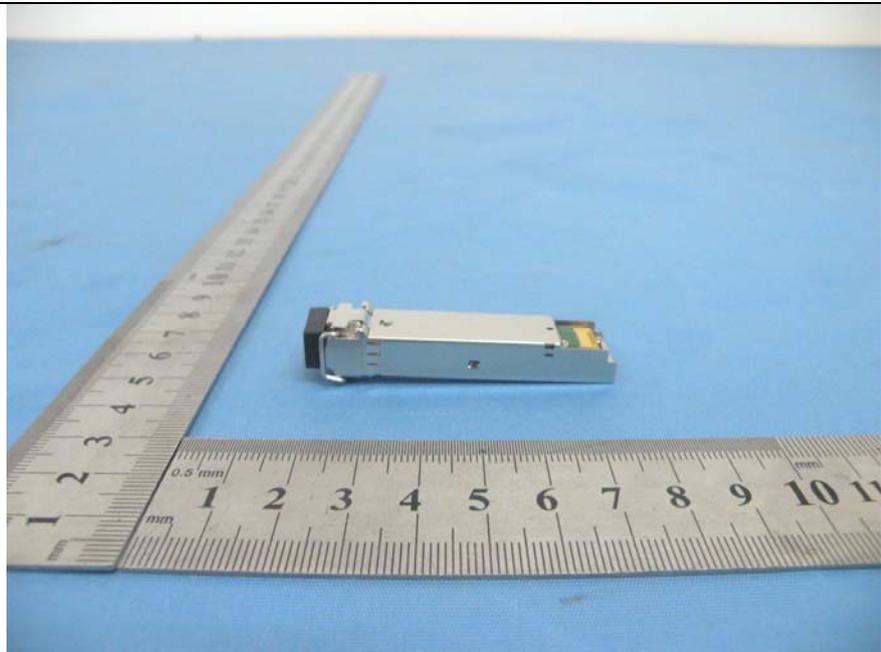
Top View [ ]

Bottom View [ ]

Left View [✓]

Right View [ ]

Inside View [ ]



**Figure 6**

Photo of EUT

Front View [ ]

Rear View [ ]

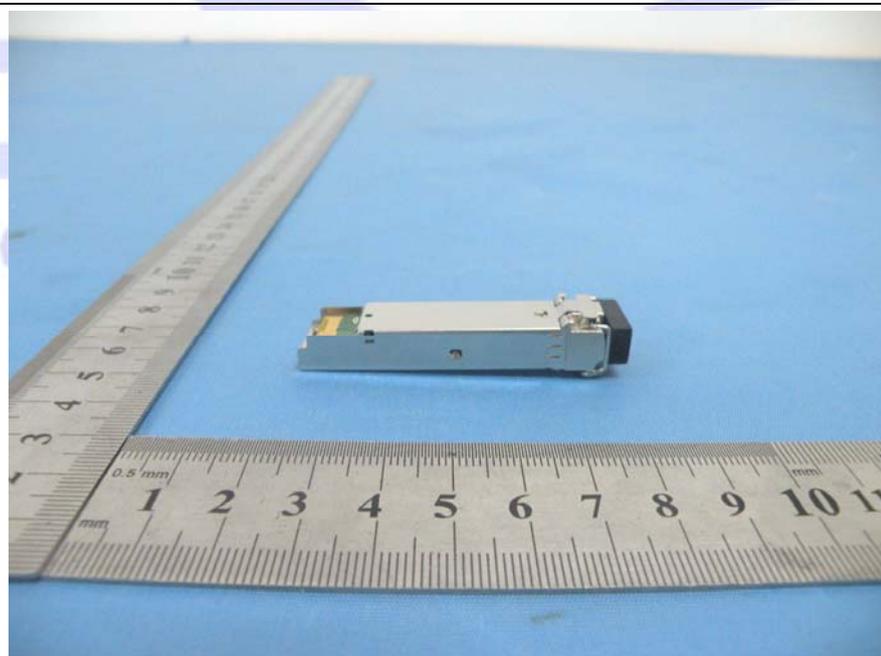
Top View [ ]

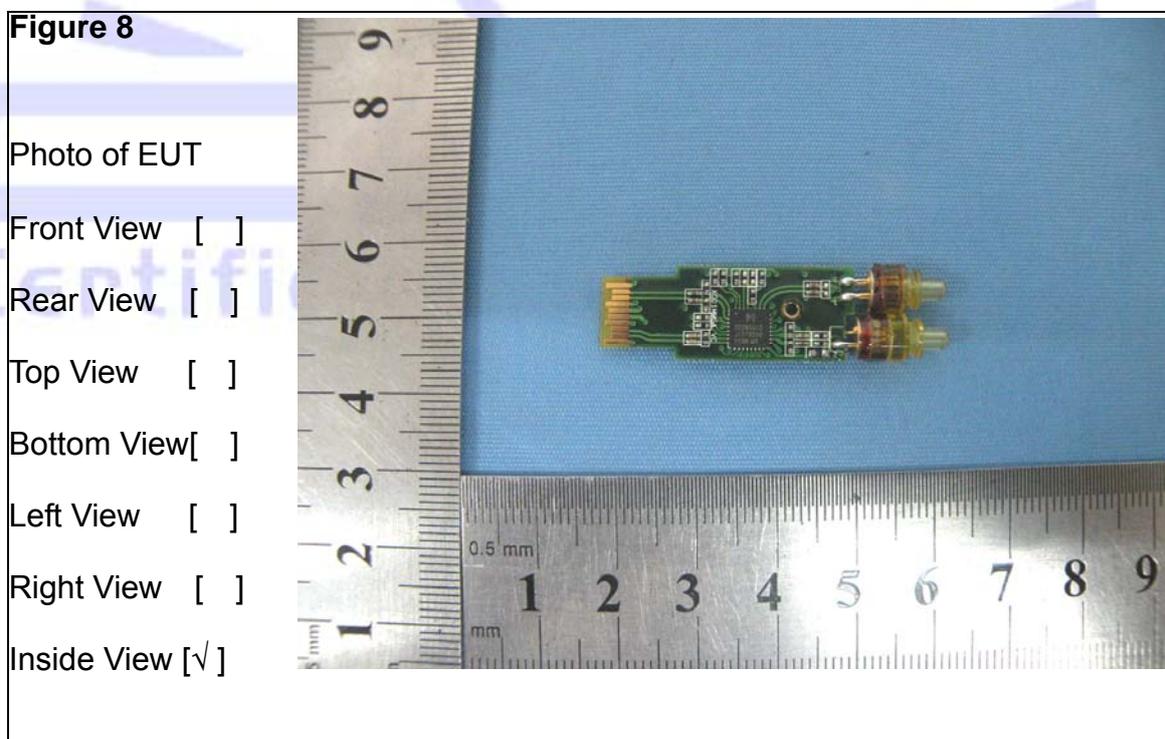
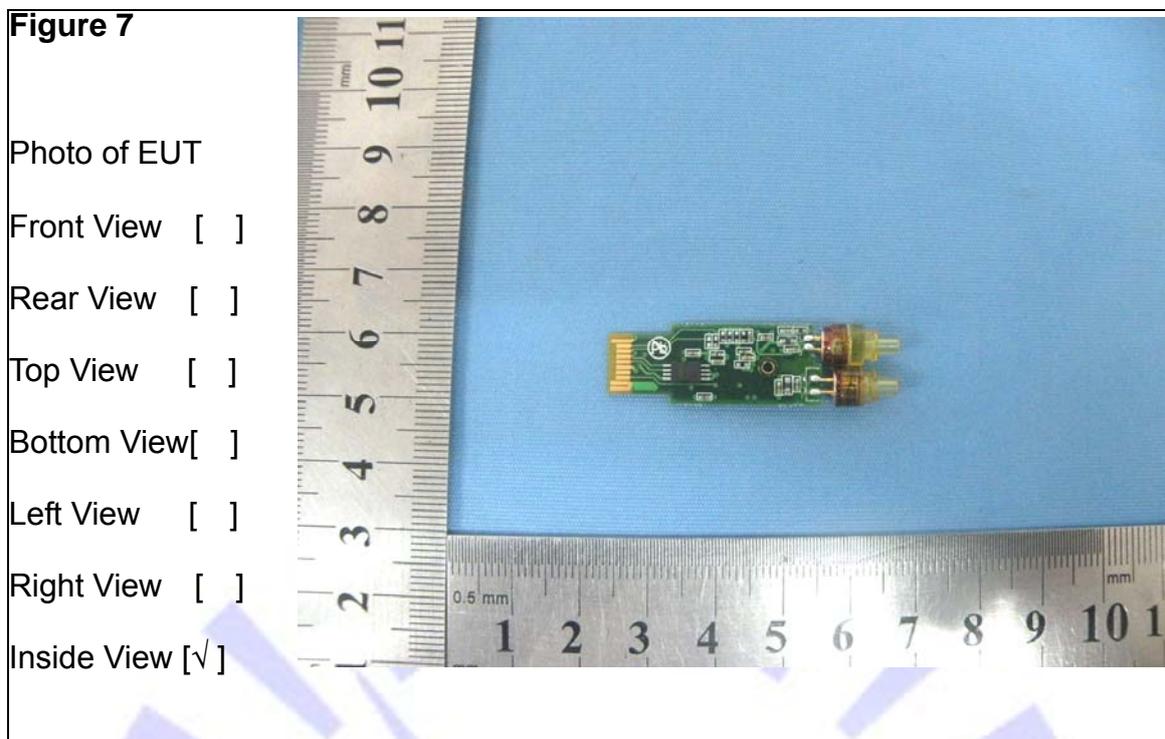
Bottom View [ ]

Left View [ ]

Right View [✓]

Inside View [ ]





----- End of the report -----